

Quantification of second layer contributions in LEIS

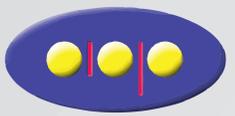
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Motivation:

- Low Energy Ion Scattering (LEIS) widely used tool to analyse surface composition and structure.
- Noble gas ions as projectiles → supreme surface sensitivity due to efficient neutralization inside the target.
- Depending on target / projectile / energy: contribution from deeper layers possible.
- Is it possible to quantify contributions from second layer?
- How does the relative contribution from different layers depend on the primary energy?

Ion yield Y^+ :

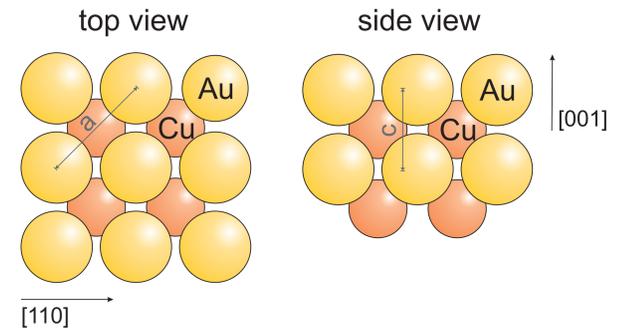
$$Y^+ = I_0 \cdot n \cdot \underbrace{\frac{d\sigma}{d\Omega}}_{Y_B} \cdot d\Omega \cdot \eta \cdot P^+$$

I_0 : Number of projectiles P^+ : Ion fraction
 n : Surface areal density $d\Omega$: Detector solid angle
 $\frac{d\sigma}{d\Omega}$: Scattering cross sec. η : Detector efficiency
 Y_B : Backscattered yield

For a given target, one can obtain the ratio of ion fractions from the ratio of ion yields when the ratio of backscattered yields is known

$$\frac{Y_{Cu}^+}{Y_{Au}^+} = \frac{Y_{B,Cu}}{Y_{B,Au}} \cdot \frac{P_{Cu}^+}{P_{Au}^+}$$

Target: $Cu_{0.5}Au_{0.5}(001)$



$Cu_{0.5}Au_{0.5}(001)$: tetragonal geometry
 $a = 3.875$, $c/a = 0.924$
 alternating layers of Au and Cu

Perfect sample to investigate 2nd layer contributions. Large mass difference between Cu and Au permits to decompose ion signal.

2 keV He^+ scattered from CuAu(001)

Experiment

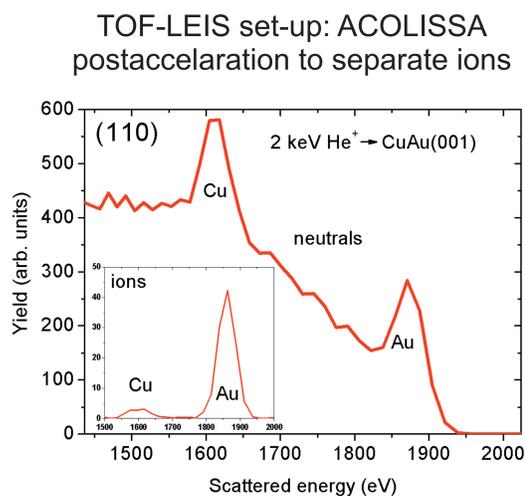


Fig. 1: Experimental spectrum of 2 keV He ions scattered from CuAu(001) - [110] azimuth. Au and Cu can be separated easily.

Evaluation

$$\frac{Y_{Cu}^+}{Y_{Au}^+} = \frac{Y_{B,Cu}}{Y_{B,Au}} \cdot \frac{P_{Cu}^+}{P_{Au}^+}$$

$$\frac{P_{Cu}^+}{P_{Au}^+} \approx 0.21$$

P_{Au}^+ can be determined from experimental spectrum. This permits to explicitly calculate P_{Cu}^+ :

$$P_{Au}^+ = 0.196 \quad P_{Cu}^+ = 0.042$$

From comparison of scattering cross sections for Cu and Au with the simulated spectrum a significant focussing effect can be deduced:

$$\frac{d\sigma_{Au}}{d\Omega} / \frac{d\sigma_{Cu}}{d\Omega} = 3.1 \quad \frac{Y_{B,Au}}{Y_{B,Cu}} = 2.1$$

MD-Simulation

Simulation package: KALYPSO
 interaction: ZBL Potential

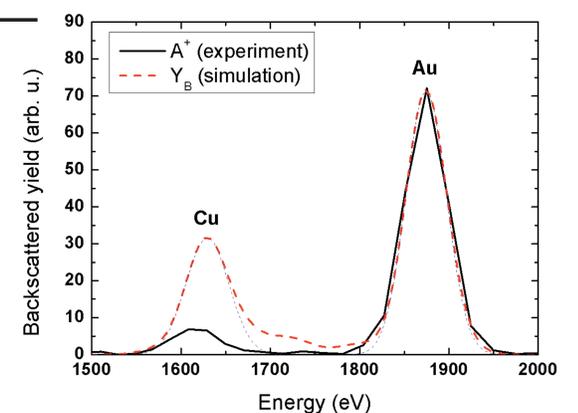


Fig. 2: Simulated spectrum of backscattered particles without consideration of charge exchange

Energy dependence:

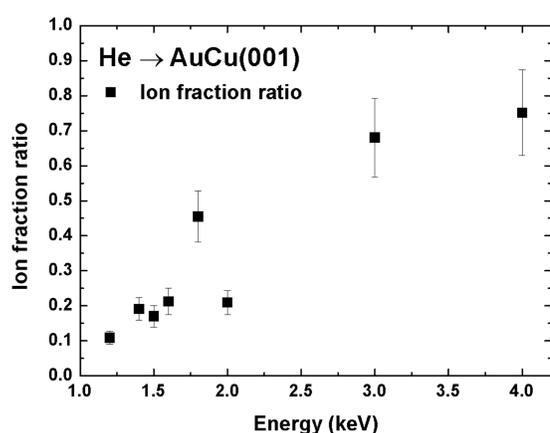


Fig. 3: Ion fraction ratio evaluated for different energies. Note, how the ratio and consequently the relative contributions from the 2nd layer increase with energy.

Charge exchange:

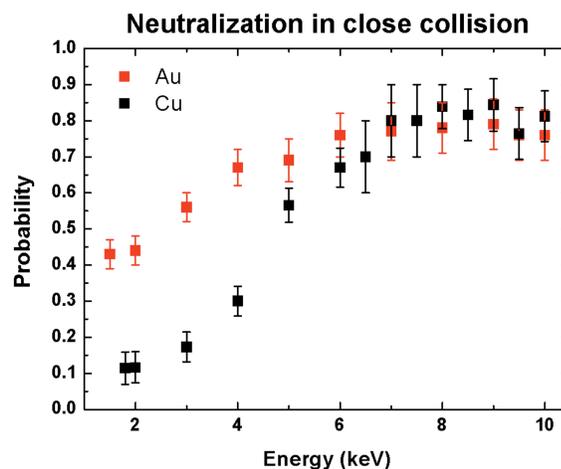


Fig. 4: Probability of neutralization in a close collision for He/Au and He/Cu. One can see the substantial difference, especially at energies < 5 keV.

Conclusion:

- For low energies, information is reduced to outermost atomic layers, with only small relative contributions from 2nd layer atoms.
- At higher energies, ion signal can contain substantial contribution from 2nd layer.
- Increased contributions from 2nd layer due to different neutralization probabilities in close collisions.
- Determination of information depth in LEIS experiments requires accurate knowledge of charge exchange processes.

Acknowledgement:

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